



Integrated Device Technology, Inc.

3.3V CMOS 16-BIT REGISTERED TRANSCEIVER

IDT74FCT163952A/B/C

FEATURES:

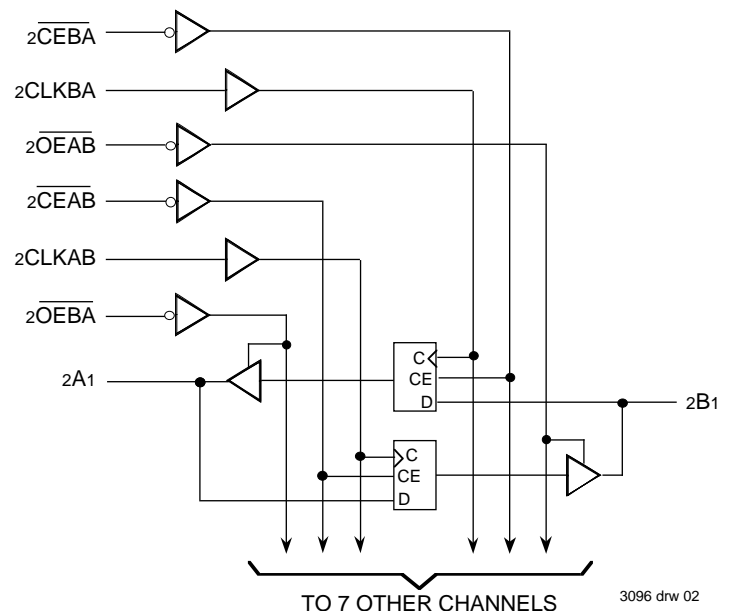
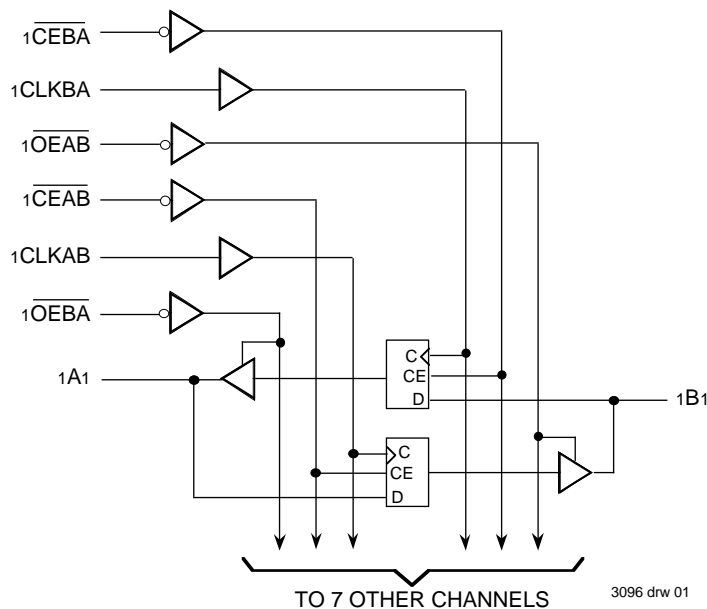
- 0.5 MICRON CMOS Technology
- **Typical tsk(o) (Output Skew) < 250ps**
- ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model (C = 200pF, R = 0)
- Packages include 25 mil pitch SSOP, 19.6 mil pitch TSSOP and 15.7 mil pitch TVSOP
- Extended commercial range of -40°C to +85°C
- VCC = 3.3V ±0.3V, Normal Range or VCC = 2.7 to 3.6V, Extended Range
- CMOS power levels (0.4µW typ. static)
- Rail-to-Rail output swing for increased noise margin
- Low Ground Bounce (0.3V typ.)
- Inputs (except I/O) can be driven by 3.3V or 5V components

DESCRIPTION:

The FCT163952A/B/C 16-bit registered transceivers are built using advanced dual metal CMOS technology. These high-speed, low-power devices are organized as two independent 8-bit D-type registered transceivers with separate input and output control for independent control of data flow in either direction. For example, the A-to-B Enable (\overline{xCEAB}) must be LOW to enter data from the A port. $xCLKAB$ controls the clocking function. When $xCLKAB$ toggles from LOW-to-HIGH, the data present on the A port will be clocked into the register. \overline{xOEAB} performs the output enable function on the B port. Data flow from the B port to A port is similar but requires using \overline{xCEBA} , $xCLKBA$, and \overline{xOEBA} inputs. Full 16-bit operation is achieved by tying the control pins of the independent transceivers together.

The FCT163952A/B/C have series current limiting resistors. These offer low ground bounce, minimal undershoot, and controlled output fall times—reducing the need for external series terminating resistors.

FUNCTIONAL BLOCK DIAGRAM

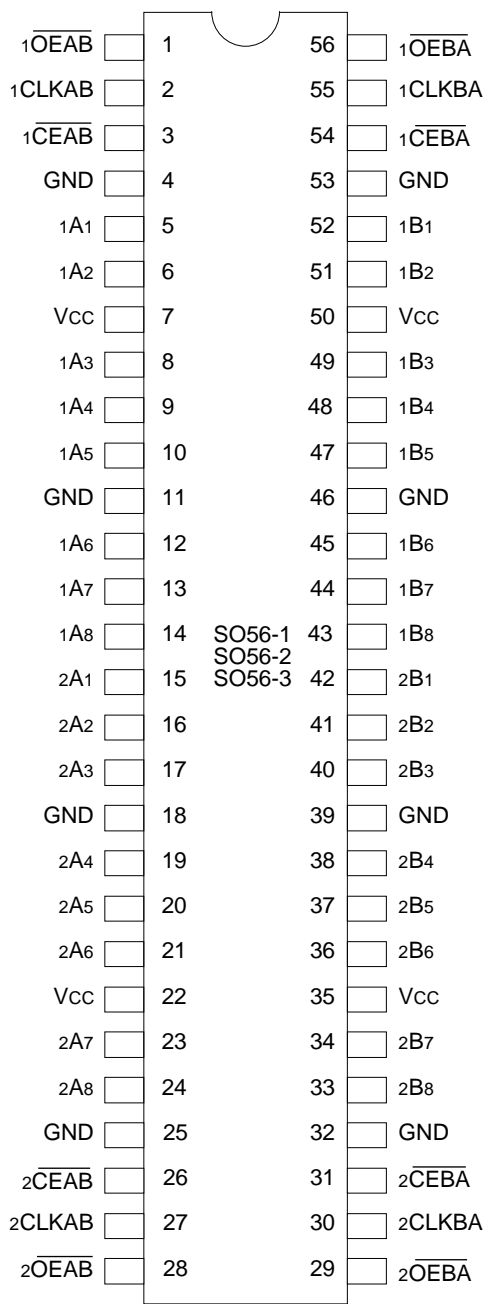


The IDT Logo is a registered trademark of Integrated Device Technology, Inc.

COMMERCIAL TEMPERATURE RANGE

AUGUST 1996

PIN CONFIGURATIONS



SSOP/
TSSOP/TVSOP
TOP VIEW

3096 drw 03

CAPACITANCE (TA = +25°C, f = 1.0MHz)

| Symbol | Parameter ⁽¹⁾ | Conditions | Typ. | Max. | Unit |
|------------------|--------------------------|-----------------------|------|------|------|
| C _{IN} | Input Capacitance | V _{IN} = 0V | 3.5 | 6.0 | pF |
| C _{I/O} | I/O Capacitance | V _{OUT} = 0V | 3.5 | 8.0 | pF |

NOTE:

1. This parameter is measured at characterization but not tested.

3096 Ink 04

PIN DESCRIPTION

| Pin Names | Description |
|---------------------|--|
| x \overline{OEAB} | A-to-B Output Enable Input (Active LOW) |
| x \overline{OEBA} | B-to-A Output Enable Input (Active LOW) |
| x \overline{CEAB} | A-to-B Clock Enable Input (Active LOW) |
| x \overline{CEBA} | B-to-A Clock Enable Input (Active LOW) |
| xCLKAB | A-to-B Clock Input |
| xCLKBA | B-to-A Clock Input |
| xAx | A-to-B Data Inputs or B-to-A 3-State Outputs |
| xBx | B-to-A Data Inputs or A-to-B 3-State Outputs |

3096 tbl 01

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

| Symbol | Description | Max. | Unit |
|----------------------------------|--------------------------------------|-------------------------------|------|
| V _{TERM} ⁽²⁾ | Terminal Voltage with Respect to GND | -0.5 to +4.6 | V |
| V _{TERM} ⁽³⁾ | Terminal Voltage with Respect to GND | -0.5 to +7.0 | V |
| V _{TERM} ⁽⁴⁾ | Terminal Voltage with Respect to GND | -0.5 to V _{CC} + 0.5 | V |
| T _{STG} | Storage Temperature | -65 to +150 | °C |
| I _{OUT} | DC Output Current | -60 to +60 | mA |

NOTES:

3096 Ink 03

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- V_{CC} terminals.
- Input terminals.
- Output and I/O terminals.

FUNCTION TABLE^(1,3)

| Inputs | | | | Outputs |
|---------------------|--------|---------------------|-----|------------------|
| x \overline{CEAB} | xCLKAB | x \overline{OEAB} | xAx | xBx |
| H | X | L | X | B ⁽²⁾ |
| X | L | L | X | B ⁽²⁾ |
| L | ↑ | L | L | L |
| L | ↑ | L | H | H |
| X | X | H | X | Z |

NOTES:

3096 tbl 02

- A-to-B data flow is shown: B-to-A data flow is similar but uses, x \overline{CEBA} , xCLKBA, and x \overline{OEBA} .
- Level of B before the indicated steady-state input conditions were established.
- H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
↑ = LOW-to-HIGH Transition
Z = High-impedance

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Commercial: $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$, $V_{CC} = 2.7\text{V}$ to 3.6V

| Symbol | Parameter | Test Conditions ⁽¹⁾ | | Min. | Typ. ⁽²⁾ | Max. | Unit |
|-------------------------------------|--|--|--------------------------|--------------------|---------------------|--------------|---------------|
| V_{IH} | Input HIGH Level (Input pins) | Guaranteed Logic HIGH Level | | 2.0 | — | 5.5 | V |
| | Input HIGH Level (I/O pins) | | | 2.0 | — | $V_{CC}+0.5$ | |
| V_{IL} | Input LOW Level (Input and I/O pins) | Guaranteed Logic LOW Level | | -0.5 | — | 0.8 | V |
| I_{IH} | Input HIGH Current (Input pins) | $V_{CC} = \text{Max.}$ | $V_I = 5.5\text{V}$ | — | — | ± 1 | μA |
| | Input HIGH Current (I/O pins) | | $V_I = V_{CC}$ | — | — | ± 1 | |
| I_{IL} | Input LOW Current (Input pins) | | $V_I = \text{GND}$ | — | — | ± 1 | |
| | Input LOW Current (I/O pins) | | $V_I = \text{GND}$ | — | — | ± 1 | |
| I_{OZH} | High Impedance Output Current (3-State Output pins) | $V_{CC} = \text{Max.}$ | $V_O = V_{CC}$ | — | — | ± 1 | μA |
| I_{OZL} | | | $V_O = \text{GND}$ | — | — | ± 1 | |
| V_{IK} | Clamp Diode Voltage | $V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$ | | — | -0.7 | -1.2 | V |
| I_{ODH} | Output HIGH Current | $V_{CC} = 3.3\text{V}, V_{IN} = V_{IH}$ or $V_{IL}, V_O = 1.5\text{V}^{(3)}$ | | -36 | -60 | -110 | mA |
| I_{ODL} | Output LOW Current | $V_{CC} = 3.3\text{V}, V_{IN} = V_{IH}$ or $V_{IL}, V_O = 1.5\text{V}^{(3)}$ | | 50 | 90 | 200 | mA |
| V_{OH} | Output HIGH Voltage | $V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL} | $I_{OH} = -0.1\text{mA}$ | $V_{CC}-0.2$ | — | — | V |
| | | | $I_{OH} = -3\text{mA}$ | 2.4 | 3.0 | — | |
| | | $V_{CC} = 3.0\text{V}$ $V_{IN} = V_{IH}$ or V_{IL} | $I_{OH} = -8\text{mA}$ | 2.4 ⁽⁵⁾ | 3.0 | — | |
| V_{OL} | Output LOW Voltage | $V_{CC} = \text{Min.}$ $V_{IN} = V_{IH}$ or V_{IL} | $I_{OL} = 0.1\text{mA}$ | — | — | 0.2 | V |
| | | | $I_{OL} = 16\text{mA}$ | — | 0.2 | 0.4 | |
| | | | $I_{OL} = 24\text{mA}$ | — | 0.3 | 0.55 | |
| | | $V_{CC} = 3.0\text{V}$ $V_{IN} = V_{IH}$ or V_{IL} | $I_{OL} = 24\text{mA}$ | — | 0.3 | 0.50 | |
| I_{OS} | Short Circuit Current ⁽⁴⁾ | $V_{CC} = \text{Max.}, V_O = \text{GND}^{(3)}$ | | -60 | -135 | -240 | mA |
| V_H | Input Hysteresis | — | | — | 150 | — | mV |
| I_{CCL} I_{CCH} I_{CCZ} | Quiescent Power Supply Current | $V_{CC} = \text{Max.},$ $V_{IN} = \text{GND}$ or V_{CC} | | — | 0.1 | 10 | μA |

3096 Ink 05

NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 3.3\text{V}, +25^{\circ}\text{C}$ ambient.
- Not more than one output should be tested at one time. Duration of the test should not exceed one second.
- This parameter is guaranteed but not tested.
- $V_{OH} = V_{CC} - 0.6\text{V}$ at rated current.

POWER SUPPLY CHARACTERISTICS

| Symbol | Parameter | Test Conditions ⁽¹⁾ | | Min. | Typ. ⁽²⁾ | Max. | Unit |
|-----------------|---|---|--|------|---------------------|--------------------|-----------------|
| ΔI_{CC} | Quiescent Power Supply | $V_{CC} = \text{Max.}$ | $V_{IN} = V_{CC} - 0.6V^{(3)}$ | — | 2.0 | 100 | μA |
| I_{CCD} | Dynamic Power Supply Current ⁽⁴⁾ | $V_{CC} = \text{Max.}$, Outputs Open $x\overline{OEAB}$ or $xOEBA = GND$ One Input Toggling 50% Duty Cycle | $V_{IN} = V_{CC}$ $V_{IN} = GND$ | — | 60 | 100 | $\mu A/$ MHz |
| I_C | Total Power Supply Current ⁽⁶⁾ | $V_{CC} = \text{Max.}$, Outputs Open $f_{CP} = 10\text{MHz}$ ($xCLKAB$) 50% Duty Cycle $x\overline{OEAB} = xCEAB = GND$ $xOEBA = V_{CC}$ One Bit Toggling $f_i = 5\text{MHz}$ 50% Duty Cycle | $V_{IN} = V_{CC}$ $V_{IN} = GND$ | — | 0.6 | 1.0 | mA |
| | | | $V_{IN} = V_{CC} - 0.6V$ $V_{IN} = GND$ | — | 0.6 | 1.1 | |
| | | $V_{CC} = \text{Max.}$, Outputs Open $f_{CP} = 10\text{MHz}$ ($xCLKAB$) 50% Duty Cycle $x\overline{OEAB} = xCEAB = GND$ $xOEBA = V_{CC}$ Sixteen Bits Toggling $f_i = 2.5\text{MHz}$ 50% Duty Cycle | $V_{IN} = V_{CC}$ $V_{IN} = GND$ | — | 3.0 | 5.0 ⁽⁵⁾ | |
| | | | $V_{IN} = V_{CC} - 0.6V$ $V_{IN} = GND$ | — | 3.0 | 5.9 ⁽⁵⁾ | |

3096 tbl 07

NOTES:

- For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{CC} = 3.3V$, $+25^\circ C$ ambient.
- Per TTL driven input; all other inputs at V_{CC} or GND .
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the I_C formula. These limits are guaranteed but not tested.
- $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
 $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP} N_{CP} / 2 + f_i N_i)$
 I_{CC} = Quiescent Current (I_{CCL} , I_{CCH} and I_{CCZ})
 ΔI_{CC} = Power Supply Current for a TTL High Input
 D_H = Duty Cycle for TTL Inputs High
 N_T = Number of TTL Inputs at D_H
 I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)
 f_{CP} = Clock Frequency for Register Devices (Zero for Non-Register Devices)
 N_{CP} = Number of Clock Inputs at f_{CP}
 f_i = Input Frequency
 N_i = Number of Inputs at f_i

SWITCHING CHARACTERISTICS OVER OPERATING RANGE⁽⁵⁾

| Symbol | Parameter | Condition ⁽¹⁾ | FCT163952A | | FCT163952B | | FCT163952C | | Unit |
|--------------|--|--------------------------|---------------------|------|---------------------|------|---------------------|------|------|
| | | | Min. ⁽²⁾ | Max. | Min. ⁽²⁾ | Max. | Min. ⁽²⁾ | Max. | |
| tPLH tPHL | Propagation Delay xCLKAB, xCLKBA to xBx, xAx | CL = 50pF RL = 500Ω | 2.0 | 10.0 | 2.0 | 7.5 | 2.0 | 6.3 | ns |
| tPZH tPZL | Output Enable Time xOEBA, xOEAB to xAx, xBx | | 1.5 | 10.5 | 1.5 | 8.0 | 1.5 | 7.0 | ns |
| tPHZ tPLZ | Output Disable Time xOEBA, xOEAB to xAx, xBx | | 1.5 | 10.0 | 1.5 | 7.5 | 1.5 | 6.5 | ns |
| tsu | Set-up Time HIGH or LOW xAx, xBx to xCLKAB, xCLKBA | | 2.5 | — | 2.5 | — | 2.5 | — | ns |
| th | Hold Time HIGH or LOW xAx, xBx to xCLKAB, xCLKBA | | 2.0 | — | 1.5 | — | 1.5 | — | ns |
| tsu | Set-up Time HIGH or LOW xCEAB, xCEBA to xCLKAB, xCLKBA | | 3.0 | — | 3.0 | — | 3.0 | — | ns |
| th | Hold Time HIGH or LOW xCEAB, xCEBA to xCLKAB, xCLKBA | | 2.0 | — | 2.0 | — | 2.0 | — | ns |
| tw | Pulse Width HIGH or LOW xCLKAB or xCLKBA ⁽⁴⁾ | | 3.0 | — | 3.0 | — | 3.0 | — | ns |
| tsk(o) | Output Skew ⁽³⁾ | | — | 0.5 | — | 0.5 | — | 0.5 | ns |

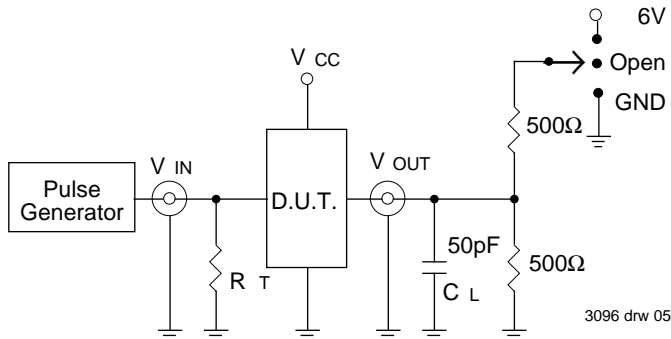
NOTES:

3096 tbl 08

1. See test circuits and waveforms.
2. Minimum limits are guaranteed but not tested on Propagation Delays.
3. Skew between any two outputs of the same package switching in the same direction. This parameter is guaranteed by design.
4. This parameter is guaranteed but not tested.
5. Propagation Delays and Enable/Disable times are with $V_{CC} = 3.3V \pm 0.3V$, Normal Range. For $V_{CC} = 2.7V$ to $3.6V$, Extended Range, all Propagation Delays and Enable/Disable times should be degraded by 20%.

TEST CIRCUITS AND WAVEFORMS

TEST CIRCUITS FOR ALL OUTPUTS



SWITCH POSITION

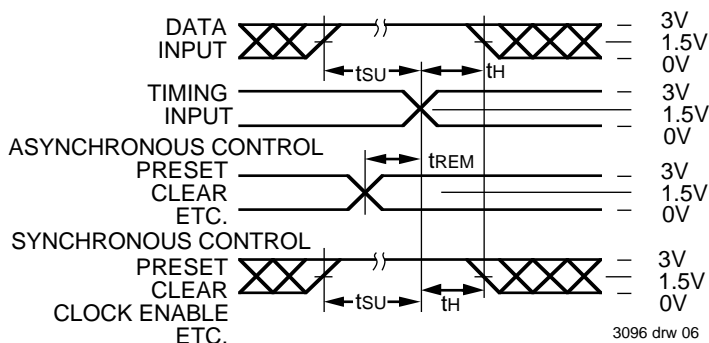
| Test | Switch |
|---|--------|
| Open Drain Disable Low Enable Low | 6V |
| Disable High Enable High | GND |
| All Other tests | Open |

DEFINITIONS:

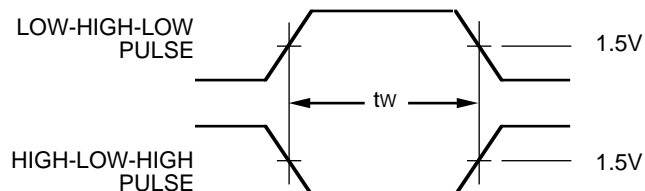
CL= Load capacitance: includes jig and probe capacitance.
RT= Termination resistance: should be equal to ZOUT of the Pulse Generator.

3096 Ink 09

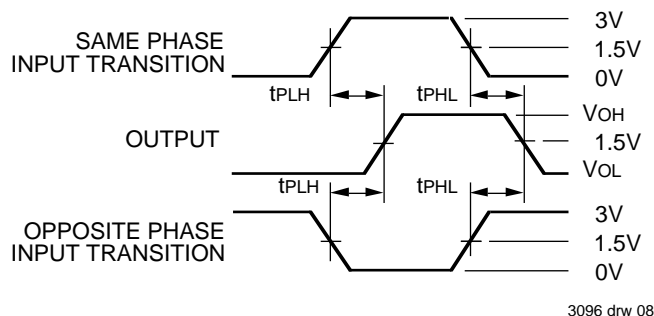
SET-UP, HOLD AND RELEASE TIMES



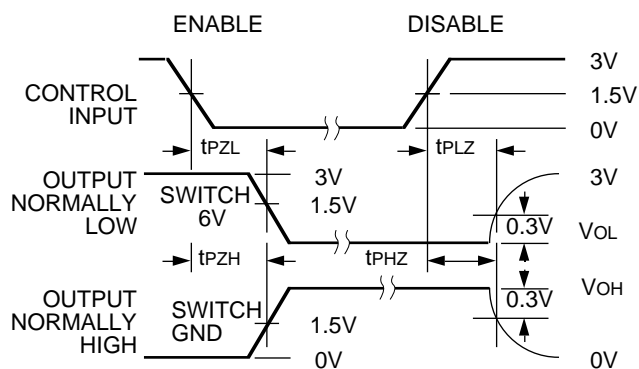
PULSE WIDTH



PROPAGATION DELAY



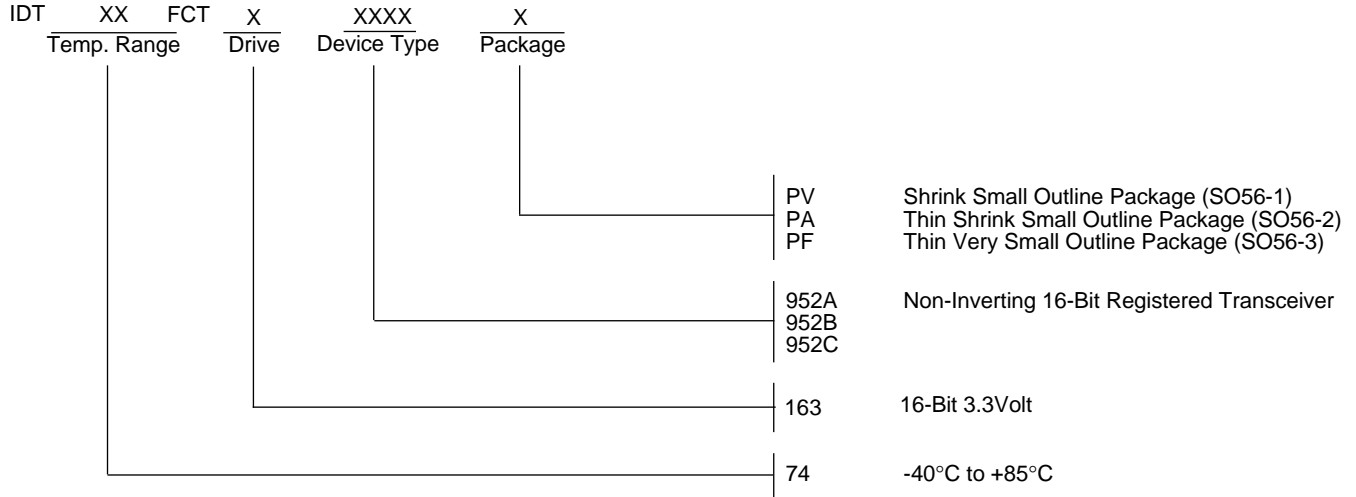
ENABLE AND DISABLE TIMES



NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
2. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$.
3. If V_{cc} is below 3V, input voltage swings should be adjusted not to exceed V_{cc} .

ORDERING INFORMATION



3096 drw 10